



# Interfacial structures and their effect on thermal conductivity and mechanical properties of diamond/Cu–B composites

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Received 21 June 2022; accepted 14 March 2023

**Abstract:** Different interfacial structures of diamond/Cu composites were synthesized by varying the boron (B) content. The microstructural, thermal, and mechanical properties of the composites were investigated. The results showed that diamond/Cu–B composites had a high thermal conductivity of 695 W/(m·K) and high bending strength of 535 MPa attributed to the formation of a micron-scale dentate B<sub>4</sub>C interface structure. The dentate B<sub>4</sub>C provided dual functions of metallurgical bonding and mechanical meshing for interface bonding. A semi-coherent interface was formed between the diamond and B<sub>4</sub>C, where the diamond (111) and B<sub>4</sub>C (104) planes were parallel. The micro/nano-scale dentate structure improved the phonon transmission efficiency and bonding strength at the interface.

**Key words:** metal matrix composites (MMCs); diamond/Cu composites; thermal conductivity; interfacial structures

## 1 Introduction

With the rapid development of high-power electronic equipment, there is a great demand for advanced thermal management materials for heat sinks and microelectronic applications [1,2]. Carbon materials (including diamond, graphene, and carbon nanotube) reinforced metal matrix composites exhibited excellent thermal conductivity in previous studies [3–5]. Among these candidates, diamond-reinforced copper matrix composites (diamond/Cu) are promising for the heat dissipation of high-power chips due to their excellent thermo-physical properties and tunable thermal expansion [6]. However, carbon and copper neither wet nor react, even at high temperatures, due to the differences in their physico-chemical properties. These properties usually result in a poor interface

between diamond and copper, further affecting the heat conduction and load transmission at the interface [7,8].

Studies have employed several routes for interface improvement to reduce the impact of weak interfaces on the thermal conductivity and mechanical properties of diamond/Cu composites. Under severe high-temperature and high-pressure preparation conditions, diamond/Cu composites might achieve coherent interfaces. YOSHIDA and MORIGAMI [9], and EKIMOV et al [10] have systematically addressed the impacts of numerous factors. The results indicated that polycrystalline diamond would be formed under high-temperature and high-pressure conditions, which is beneficial to eliminating interfaces and related defects. In addition, the fabrication of diamond/Cu composites with void-free interfaces by electroplating was proposed [11]. Although the perfect interface is the

goal pursued in diamond/Cu composites, harsh fabrication technology limits its application in industrial production.

Interfacial modification is another effective method that improves interface wetting and bonding remarkably. The carriers of heat transfer (i.e., phonons and electrons) control the heat transfer mechanisms in diamond and copper. The interface layer also acts as a phonon bridge between diamond and copper. CAO et al [12] introduced graphene as an interface layer that reduced the acoustic mismatch between diamond and copper, thus significantly improving the interfacial thermal conductivity. In addition, a new two-dimensional material MXene ( $\text{Ti}_3\text{C}_2\text{T}_x$ ) adequately improved the interfacial thermal conductivity [13]. Furthermore, carbides of some elements (such as B, Cr, Ti, W, and Zr) improved wettability, interface thermal conductivity, and interface bonding strength between diamond and copper [14–18]. These carbides can transform the interface bonding into chemical bonding, which could significantly increase the thermal conductivity and interface bonding strength. CIUPIŃSKI et al [19] have prepared diamond/Cu composites, including  $\text{Cr}_3\text{C}_2$  carbide via pulse plasma sintering, achieving the maximum thermal conductivity of  $687 \text{ W}/(\text{m}\cdot\text{K})$ . As for boron, it can be directly alloyed into the copper matrix or grown on the diamond surface as a coating, resulting in increased tensile strengths and thermal conductivities compared to the systems without boron addition [8,14]. The highest thermal conductivity of  $538 \text{ W}/(\text{m}\cdot\text{K})$  was achieved with an optimal boron content of 0.8 wt.% [20].

In addition to the thermal conductivity, the mechanical properties of diamond/Cu composites are equally important for their application. ABYZOV et al [21] developed a diamond/Cu composite with high filler content (60 vol.%) and coarse diamond particles ( $180 \mu\text{m}$ ), which exhibited a high bending strength of 380 MPa. ZHANG et al [22] obtained diamond/Cu–Zr composites with a bending strength of 440 MPa by zirconium interface modification. In previous work, 0.7 wt.% Cr addition achieved the highest tensile and bending strengths of 252 MPa and 523 MPa, respectively [15].

Studies have been focused on the scale effect of the carbide interface layer while ignoring the

influence of the interface layer structure. In this work, diamond/Cu–B composites were prepared by vacuum pressure infiltration, and an in-situ generated micro/nano-scale dentate interface structure was discovered. The effects of different dentate structures on the thermal conductivity and strength of diamond/Cu–B composites were studied. The formation process of the micro/nano-scale dentate was analyzed by microscopic means to reveal the mechanism by which the dentate improves the interface phonon transmission efficiency and the interface bonding strength. Hence, this work provides valuable guidance for the design of high-heat conduction interface structures in diamond/Cu composites.

## 2 Experimental

Pressure infiltration was performed to prepare diamond/Cu composites with different boron contents. Copper bulks (purity of 99.9 wt.%) and boron powder (size of  $2\text{--}3 \mu\text{m}$ , and purity of 99.99 wt.%) were obtained from Cuibolin Non-Ferrous Technology Co., China, and used as the composite matrix. Single crystal diamonds with a grain size of  $100 \mu\text{m}$  were obtained from Huanghe Whirlwind Co. (China) and added to the composites in 60 vol.%. First, diamond particles were made into preforms and placed in graphite molds. Using the vacuum pressure infiltration method, Cu–B alloy (0.3 wt.%, 0.5 wt.%, 0.7 wt.%, and 1.0 wt.% of B) was poured into the graphite mold at  $1250^\circ\text{C}$ . Mechanical pressure of 50 MPa was applied to forcing copper to penetrate the preform gap. The samples were kept at  $1000^\circ\text{C}$  and 50 MPa for 60 min, and then the diamond/Cu–B composites with a diameter of 100 mm were obtained. The nitric acid etching was subsequently applied to exfoliating the diamond particles in the composite. Diamond/Cu–B composites were heated to  $200^\circ\text{C}$  in 68 wt.% nitric acid for 30 min, and the diamond particles were obtained after the dissolution of the matrix copper.

The microstructures of diamond/Cu–B interfaces were analyzed using scanning electron microscopy (SEM, JSM–7610F Plus, Hitachi, Japan) and transmission electron microscopy (TEM, JEOL–2100F, Japan). Selected area electron diffraction (SAED) was used to examine the atomic

structure at the interface of the diamond/Cu–B composites. The X-ray diffraction (XRD) patterns of diamond/Cu–B composites were recorded using the X'Pert-Pro MPD diffractometer (Holland Panalytical) with Cu K $\alpha$ . The interface microstructure samples of diamond/Cu–B composites were prepared by focused ion beam etching. The thermal conductivity of diamond/Cu–B composites was calculated by

$$K = \alpha \cdot \rho_c \cdot c_p \quad (1)$$

where  $\alpha$ ,  $\rho_c$ , and  $c_p$  represent the thermal diffusivity, density and specific heat capacity of the composite, respectively. The thermal diffusivities of the diamond/Cu–B composites were measured at room temperature by a thermal conductivity tester (LFA447, NETZSCH). The densities of the diamond/Cu–B composites were measured by the drainage method. The measurement was repeated three times for each sample and averaged. The specific heat capacities of the composites were measured at room temperature by a synchronous thermal analyzer (STA 449F3, Netzsch, Germany). The bending strengths of the diamond/Cu–B composites were measured by a universal material testing machine. The testing sample size was 4 mm  $\times$  3 mm  $\times$  35 mm.

### 3 Results and discussion

#### 3.1 Microstructures and phase constitutions

The nucleation and growth of interface carbide are affected by various conditions including temperature and boron content. By controlling these parameters, in-situ controllable growth of carbides can be achieved, and thereby different interface structures are prepared. The surface morphologies of the diamond particles extracted from diamond/Cu–B composites was examined by SEM, as shown in Fig. 1. When a small amount of boron was added, one-third of the exposed defects existed on the diamond surface. Upon increasing the boron content, the size of sparse carbide protrusions reached 1  $\mu$ m. However, spot defects remained on the surface that was not covered with carbide. When the boron content reached 0.7 wt.%, a compact and uniform carbide layer was formed on the diamond surface, along with carbide dentate structures of a uniform size distribution of about 1  $\mu$ m. Further increased boron content provided

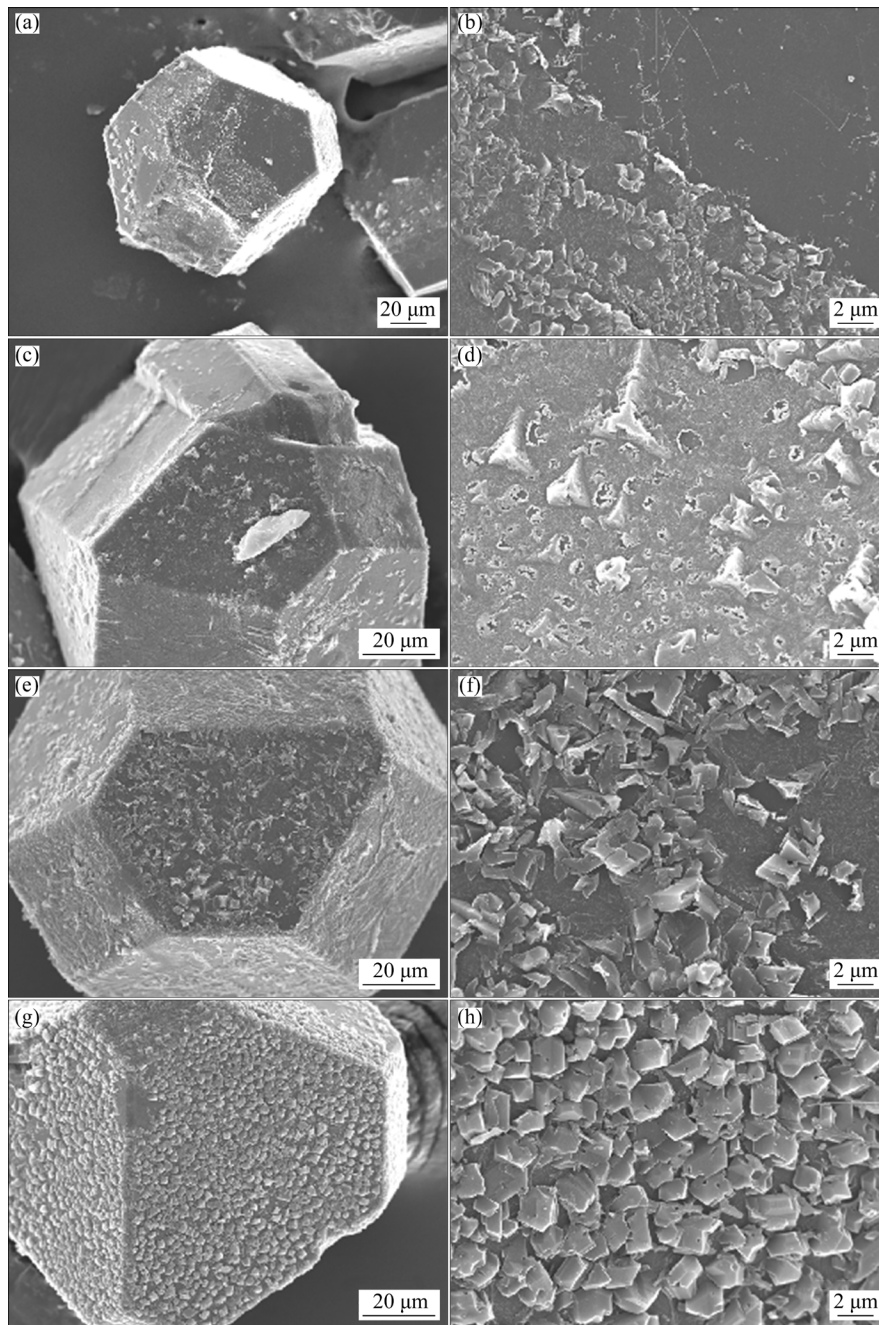
sufficient elements for carbide growth. Carbides continued to grow perpendicular to the diamond surface, with dentate structures up to 1.5  $\mu$ m. With this structure, the dense carbide layer on the surface massively reduced the interface thermal resistance. Simultaneously, diffusion bonding and physical-mechanical meshing combined the dentate carbide and the matrix.

To confirm the composition of dentate carbide at the interface of diamond/Cu–B composites, the phase compositions of the polished surfaces (Fig. 2(a)) and the elemental composition of the near-interface region were measured by XRD and EDS. As depicted in Fig. 2(b), significant boron accumulation was detected near the diamond interface region, which indicates that boron diffuses from the copper–boron solid solution to the diamond during the infiltration process. Further, phase analyses have shown that a newly formed phase of B $_4$ C was detected except for the copper and diamond phases in Fig. 3. Hence, it is confirmed that B $_4$ C is the product of the interface reaction during the infiltration process of the diamond/Cu–B composites. The presence of B $_4$ C enhances the interfacial bonding between diamond and copper, as inferred from the fracture morphology.

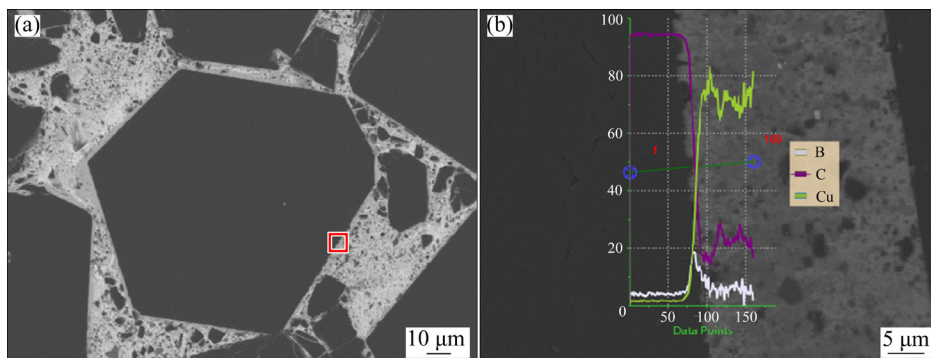
The fracture structures of the diamond/Cu–B composites with different boron contents are shown in Fig. 4. Increasing the boron content enhanced the proportion of diamond transgranular fractures within the fracture structure. When the boron content was lower than 0.5 wt.%, the fracture was dominated by diamond extraction. Part of the carbide adhered to the extracted diamond surface, and the uniform layer was not formed in carbide. Hence, carbides were insufficient to provide strong interfacial bonding. When the boron content was increased to 0.7 wt.%, the proportion of diamond transgranular fracture within the fracture increased, and more carbides adhered to the extracted diamond surface. Further enhancement of the boron content to 1.0 wt.% promoted transgranular fracture in the diamond, indicating that the interfacial bonding force became stronger.

#### 3.2 Interface characterization

The interface microstructures of the diamond/Cu–B composites were revealed by TEM. High-resolution atomic images were obtained to reveal

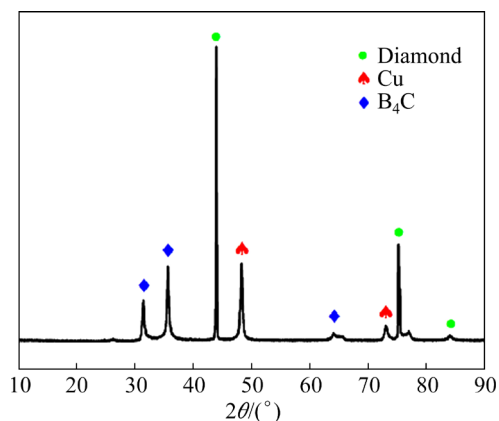


**Fig. 1** SEM images revealing surface morphologies of diamond particles extracted from diamond/Cu–B composites at different boron (B) contents: (a, b) 0.3 wt.% B; (c, d) 0.5 wt.% B; (e, f) 0.7 wt.% B; (g, h) 1.0 wt.% B



**Fig. 2** SEM image for polished surface of diamond/Cu–B composites (a) and element analysis of interface area (b)



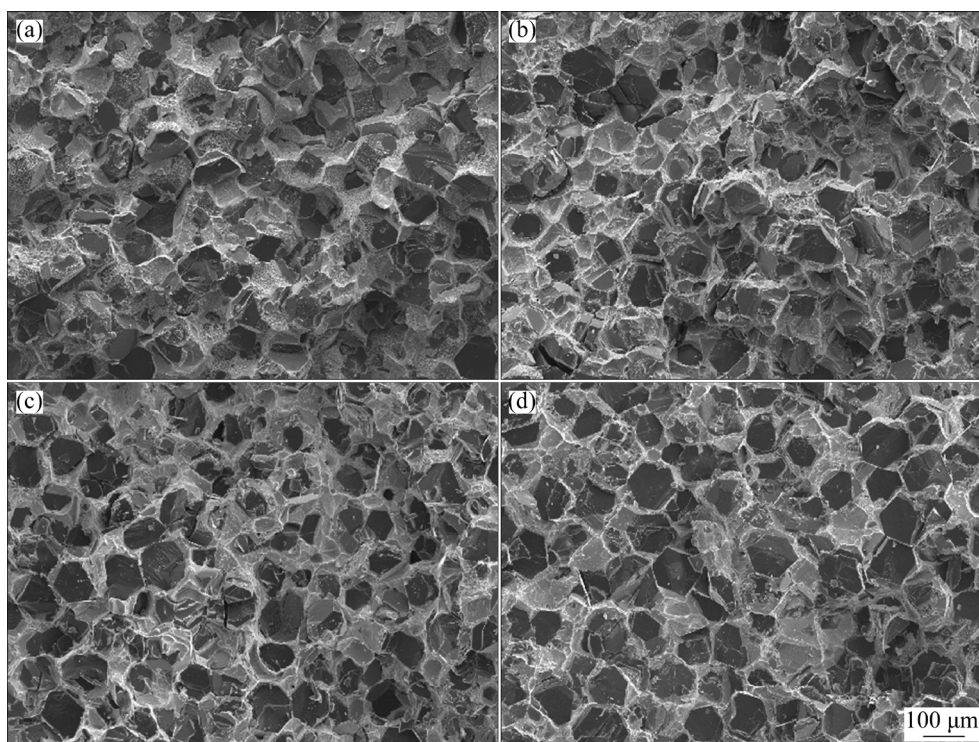


**Fig. 3** XRD pattern of diamond/Cu-B composites

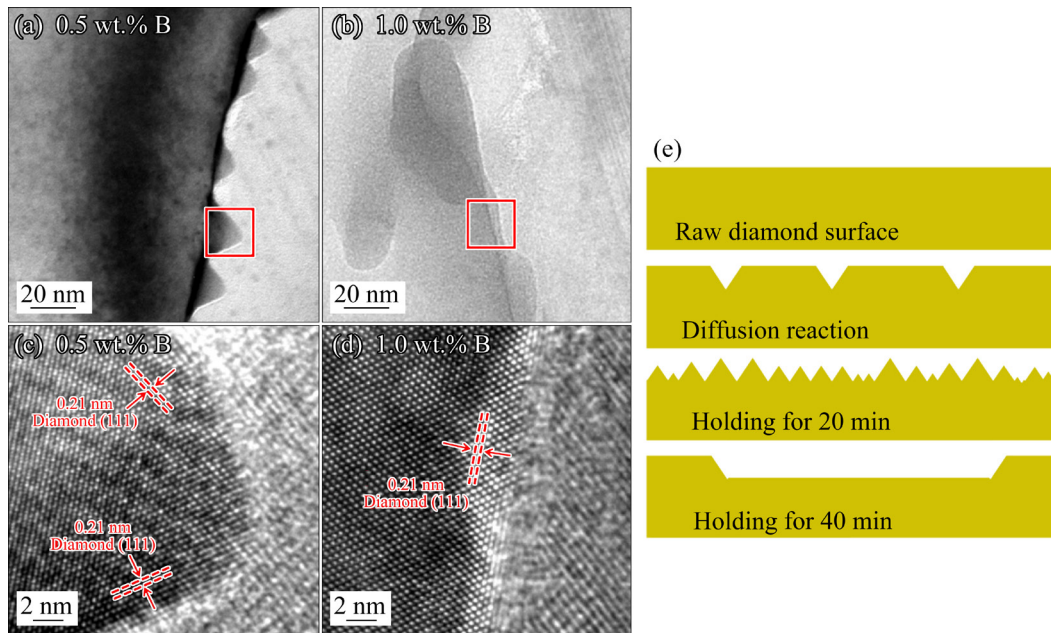
the interfacial bonding between diamond and  $B_4C$ . Figure 5(a) shows that a tooth structure appeared between the diamond and  $B_4C$  when the boron addition was 0.5 wt.%. With increasing the boron content, the tooth structure at the interface disappeared, as shown in Fig. 5(b). A straight and clear interface was formed between the diamond and  $B_4C$ . The diamond crystal planes parallel to the interface were designated as diamond (111) planes. The high-resolution atomic image in Fig. 5(c) shows that the dentate structure was composed of diamond atoms. The diamond crystal plane parallel to the interface was demarcated as the (111) plane

with an interplanar distance of 0.206 nm. Interestingly, the orientations of the faces where the dentate structure binds to  $B_4C$  were all diamond (111) faces. Overall, these findings indicate the evolution of the interface between diamond and  $B_4C$  during the infiltration process in diamond/Cu-B composites.

Figure 5(e) graphically depicts the changes affecting the diamond surface and the interface microstructure evolution between diamond and  $B_4C$  during infiltration. Initially, the surface of the diamond particles was flat. Upon exposure to the molten Cu-B alloy, the carbon atoms on the diamond surface began to fall off along the diamond (111) surface. Since the surface energy of the diamond (111) plane is lower than the diamond (100) plane, it is easier for the (111) plane to participate in interface reactions [23,24]. The exfoliated carbon atoms reacted with the boron in the alloy to form  $B_4C$  while leaving pits on the diamond surface. With the progress of the interfacial reaction, a dentate structure was formed gradually by the pits on the surface. Then, the dentate reacted to form a flat interface until the boron in the alloy was consumed. Therefore, it is evident that the content of boron controls the interface structure between diamond and  $B_4C$ .



**Fig. 4** SEM images for fracture morphologies of diamond/Cu-B composites at different boron contents: (a) 0.3 wt.% B; (b) 0.5 wt.% B; (c) 0.7 wt.% B; (d) 1.0 wt.% B



**Fig. 5** TEM bright field images (a, b) and HRTEM images (c, d) of interface between diamond and B<sub>4</sub>C in diamond/Cu–B composites; Schematic diagram of interface microstructure evolution between diamond and B<sub>4</sub>C during infiltration (e)

To further reveal the micro-area heat transfer mechanism of the diamond/Cu–B composites interface, HRTEM and selected area electron diffraction (SAED) were used to analyze it. Figure 6(a) displays the bright-field image of the interface within diamond/Cu–B composites, where B<sub>4</sub>C had an irregular shape with an average thickness of about 300 nm. The high-resolution atomic image of the b-region (Fig. 6(b)) shows that diamond (111) and B<sub>4</sub>C (104) planes were parallel, i.e., diamond(111)//B<sub>4</sub>C(104). Figure 6(c) shows that B<sub>4</sub>C (104) plane was also parallel to the interface between B<sub>4</sub>C and copper and that 10 nm copper nanocrystals were formed on the copper matrix side. SAED was performed on the selected areas in Fig. 6(a) and the corresponding SAED patterns are shown in Figs. 6(d–f). The results confirm that the d-region is diamond and the e-region is B<sub>4</sub>C. The substrate side corresponding to the poly-crystalline ring is copper nanocrystals.

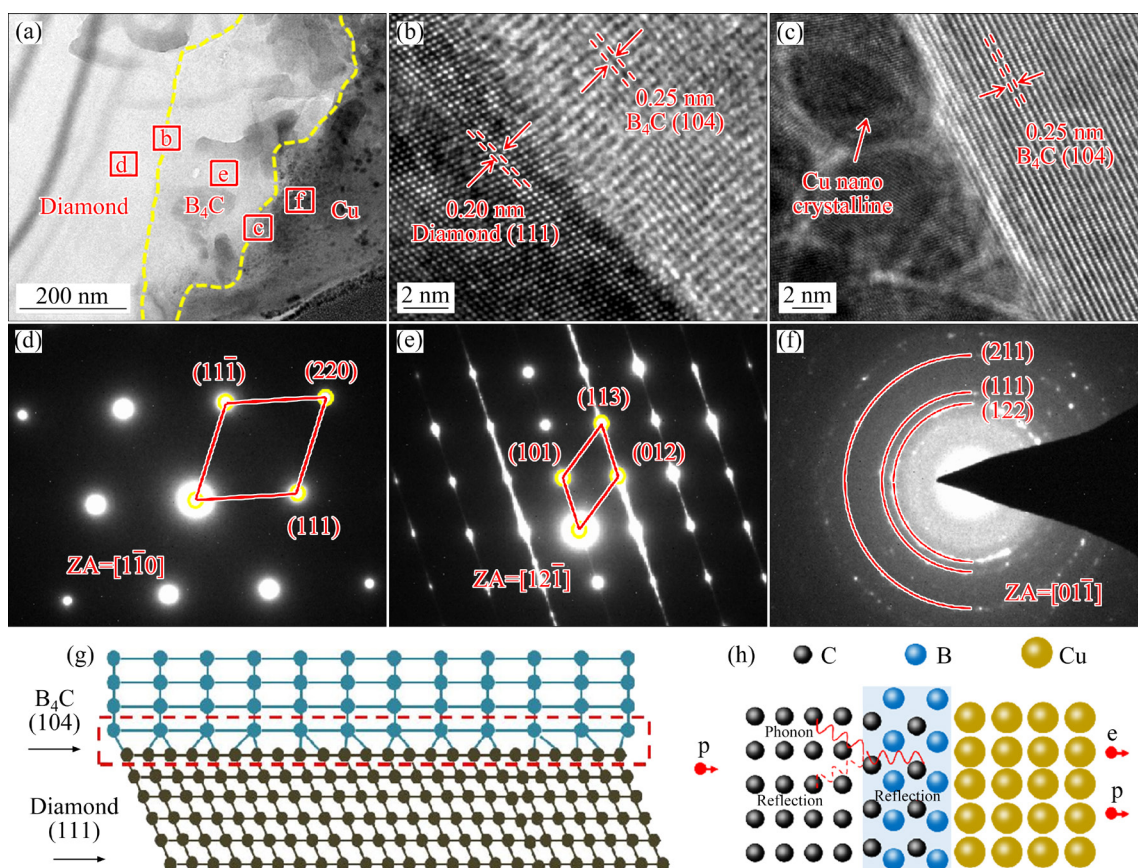
According to the interface atomic structure in Fig. 6(b), a schematic diagram of the interface bonding between diamond and B<sub>4</sub>C was established, as displayed in Fig. 6(g). Based on the orientation relationship between diamond and B<sub>4</sub>C, the lattice mismatch ( $\delta$ ) was calculated as 10.9%, where  $\delta = (d_{\text{diamond}} - d_{\text{B}_4\text{C}}) / (d_{\text{diamond}} + d_{\text{B}_4\text{C}})$ ,  $d_{\text{diamond}(111)} = 0.206$  nm,

and  $d_{\text{B}_4\text{C}(104)} = 0.256$  nm [25]. The interface between B<sub>4</sub>C and diamond is semi-coherent and the schematic diagram of the atomic matching model is shown in Fig. 6(g). The semi-coherent interface effectively reduced phonon scattering, thereby improving interface thermal conductivity. The schematic diagram of the interface phonon transport is shown in Fig. 6(h). However, the phonons reflected during phonon transmission in the tooth-shaped interface structure could re-enter the interface. Overall, this interface structure improved the phonon transmission efficiency, and thus it could also effectively improve the interface thermal conductivity [26].

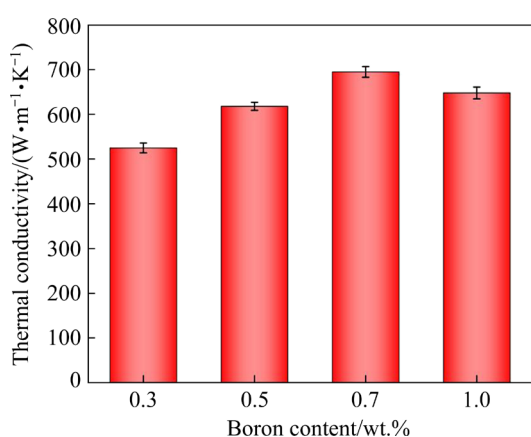
### 3.3 Properties

The effect of boron content on the thermal conductivity of diamond/Cu–B composites is exhibited in Fig. 7. With increasing the boron content, the thermal conductivity firstly increased and then decreased, displaying a maximum value of 695 W/(m·K) at 0.7 wt.% boron content. The functional relationship between thermal conductivity and boron content can be interpreted by the interface structure. The thermal conductivity reached its highest value when the B<sub>4</sub>C layer coated the diamond surface completely without defects.





**Fig. 6** TEM image of copper and diamond interface layer for diamond/Cu–B composites (a); High-resolution atomic image of interface between diamond and B<sub>4</sub>C (b); High-resolution atomic image of interface between copper and B<sub>4</sub>C (c); Selected area electron diffraction calibration of d-region (d), e-region (e), and f-region (f) in (a); Schematic diagram of interfacial bonding state between diamond (111) and B<sub>4</sub>C (104) (g); Schematic diagram of interface phonon transport (h)

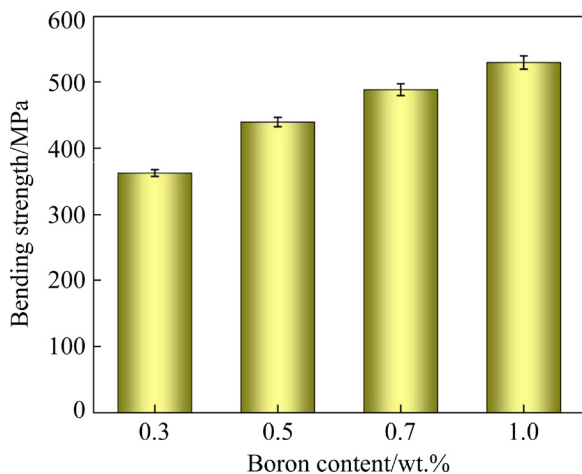


**Fig. 7** Thermal conductivity of diamond/Cu–B composites with different boron contents

Beyond the critical value, increasing the B<sub>4</sub>C layer grain augmented the interfacial thermal resistance. Therefore, further boron addition would decrease the thermal conductivity of diamond/Cu–B composites.

Figure 8 depicts the bending strength of diamond/Cu–B composites as a function of boron content. The bending strength of diamond/Cu–B composites increased linearly with the addition of boron content. Increasing the boron content from 0.3 to 1.0 wt.% enhanced the bending strength of the composites from 368 to 535 MPa. The bending strength of 535 MPa is higher than the previously reported value [22]. The improvement in bending strength is closely related to the strength of interface carbide and the near-interface area connecting diamond and copper. The size of B<sub>4</sub>C continued to increase with the addition of boron content. The dentate B<sub>4</sub>C extended to the matrix, forming mechanical engagement with the matrix, which significantly improved the bonding strength between the matrix and B<sub>4</sub>C. Copper nano-crystalline regions were detected on the matrix side near the interface region. The nanocrystals enhanced the strength of the interface region,

resulting in increased crack propagation resistance. Due to the stress concentration in the process of crack propagation, diamond transgranular fracture occurred. Therefore, the mechanical properties of diamond/Cu–B composites were significantly improved by controlling the process parameters to regulate the interface structure.



**Fig. 8** Bending strength of diamond/Cu–B composites with different boron contents

## 4 Conclusions

(1) With increasing the boron content in the alloy from 0.3 wt.% to 1.0 wt.%, the carbide structure evolved from a discontinuous point-like structure to a dentate structure with 1.5  $\mu\text{m}$  in height. The proportion of diamond transgranular fractures in the fracture structure of diamond/Cu–B composites continued to rise, which showed that the interface bonding strength increased with the change in the  $\text{B}_4\text{C}$  structure.

(2) By changing the boron content to tailor the  $\text{B}_4\text{C}$  structure, a maximal thermal conductivity of 695  $\text{W}/(\text{m}\cdot\text{K})$  was obtained at 0.7 wt.% boron addition. However, a maximal bending strength of 535 MPa was attained at 1.0 wt.% boron addition.

(3) The micron-scale dentate  $\text{B}_4\text{C}$  structure provided the dual functions of metallurgical bonding and mechanical meshing for interface bonding. The interface formed between diamond and  $\text{B}_4\text{C}$  was semi-coherent and revealed the orientation relationship of diamond(111)/ $\text{B}_4\text{C}$ (104). The micro/nano-scale dentate structure improved the interface phonon transmission efficiency and interface bonding strength, thereby improving interface heat conduction and load transmission.

## CRediT authorship contribution statement

**Zhong-nan XIE:** Conceptualization, Methodology, Writing – Original draft; **Hong GUO:** Conceptualization Funding acquisition; **Wei XIAO:** Writing – Review & editing; **Xi-min ZHANG:** Investigation; **Shu-hui HUANG:** Methodology; **Ming-mei SUN:** Validation; **Hao-feng XIE:** Funding acquisition

## Declaration of competing interest

The authors declare that they have no known competing financial interests or personal relationships that could have appeared to influence that work reported in this paper.

## Acknowledgments

This work was financially supported by the National Key Research and Development Program of China (No. 2017YFB0406202).

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## 金刚石/铜-硼复合材料界面结构及其对热导率和力学性能的影响

谢忠南<sup>1,2,3</sup>, 郭宏<sup>1,2,3</sup>, 肖伟<sup>1,2,3</sup>, 张习敏<sup>1,2,3</sup>, 黄树晖<sup>1,2,3</sup>, 孙明美<sup>1,2,3</sup>, 解浩峰<sup>1,2,3</sup>

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**摘要:** 通过控制硼含量制备不同界面结构的金刚石/铜复合材料, 研究复合材料的界面显微组织及其对热性能和力学性能的影响。结果表明, 界面处形成微米级 B<sub>4</sub>C 齿状结构, 该结构为界面结合提供冶金结合和机械啮合的双重作用。金刚石/铜-硼复合材料获得最高为 695 W/(m·K) 的热导率和 535 MPa 的弯曲强度。金刚石与 B<sub>4</sub>C 之间形成具有金刚石(111)/B<sub>4</sub>C (104) 取向关系的半共格界面。微纳米级齿状结构可提高界面声子传输效率和界面结合强度。

**关键词:** 金属基复合材料; 金刚石/铜复合材料; 热导率; 界面结构

(Edited by Bing YANG)